| 查询IRFBF20ST RRPbF供应商 |  |  |
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|  | IRFBF20S， |  |
|  |  | Po |
| PRODUCT SUMMARY |  |  |
| $\mathrm{V}_{\mathrm{DS}}$（V） | 900 |  |
| $\mathrm{R}_{\mathrm{DS} \text {（on）}}(\Omega)$ | $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$ | 8.0 |
| $\mathrm{Q}_{\mathrm{g}}$（Max．）（ nC ） | 38 |  |
| $\mathrm{Q}_{\mathrm{gs}}(\mathrm{nC})$ | 4.7 |  |
| $\mathrm{Q}_{\mathrm{gd}}(\mathrm{nC})$ | 21 |  |
| Configuration | Single |  |



## FEATURES

－Surface Mount（IRFBF20S／SiHFBF20S）
－Low－Profile Through－Hole（IRFBF20L／SiHFBF20L）

－Available in Tape and Reel RoHS＊ （IRFBF20S／SiHFBF20S）
－Dynamic dV／dt Rating
－ $150{ }^{\circ} \mathrm{C}$ Operating Temperature
－Fast Switching
－Fully Avalanche Rated
－Lead（Pb）－free Available

## DESCRIPTION

Third generation Power MOSFETs form Vishay provide the designer with the best combination of fast switching， ruggedized device design，low on－resistance and cost－effectiveness．
The D²PAK is a surface mount power package capabel of the accommodating die sizes up to HEX－4．It provides the highest power capability and the lowest possible on－resistance in any existing surface mount package．The $D^{2}$ PAK is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2．0 W in a typical surface mount application．The through－hole version（IRFBF20L／SiHFBF20L）is available for low－profile applications．

## ORDERING INFORMATION

| Package | D²PAK（TO－263） | D²PAK（TO－263） | D²PAK（TO－263） | $1^{2} \mathrm{PAK}$（TO－262） |
| :---: | :---: | :---: | :---: | :---: |
| Lead（Pb）－free | IRFBF20SPbF | IRFBF20STRLPbFa | IRFBF20STRRPbFa | IRFBF20LPbF |
|  | SiHFBF20S－E3 | SiHFBF20STL－E3 ${ }^{\text {a }}$ | SiHFBF20STR－E3 ${ }^{\text {a }}$ | SiHFBF20L－E3 |
| SnPb | IRFBF20S | IRFBF20STRL ${ }^{\text {a }}$ | IRFBF20STRR ${ }^{\text {a }}$ | IRFBF20L |
|  | SiHFBF20S－E3 | SiHFBF20STL ${ }^{\text {a }}$ | SiHFBF20STR ${ }^{\text {a }}$ | SiHFBF20L |

## Note

a．See device orientation．

| ABSOLUTE MAXIMUM RATINGS $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ ，unless otherwise noted |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| PARAMETER |  |  | SYMBOL | LIMIT | UNIT |
| Drain－Source Voltage ${ }^{\text {e }}$ |  |  | $\mathrm{V}_{\mathrm{DS}}$ | 900 | V |
| Gate－Source Voltage ${ }^{\text {e }}$ |  |  | $\mathrm{V}_{\mathrm{GS}}$ | $\pm 20$ |  |
| Continuous Drain Current | $\mathrm{V}_{\mathrm{GS}}$ at 10 V | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | $\mathrm{I}_{\mathrm{D}}$ | 1.7 | A |
|  |  | $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ |  | 1.1 |  |
| Pulsed Drain Currenta，${ }^{\text {e }}$ |  |  | $\mathrm{I}_{\mathrm{DM}}$ | 6.8 |  |
| Linear Derating Factor |  |  |  | 0.43 | W／${ }^{\circ} \mathrm{C}$ |
| Single Pulse Avalanche Energy ${ }^{\text {b，e }}$ |  |  | $\mathrm{E}_{\text {AS }}$ | 180 | mJ |
| Repetitive Avalanche Current ${ }^{\text {a }}$ |  |  | $\mathrm{I}_{\text {AR }}$ | 1.7 | A |
| Repetitive Avalanche Energy ${ }^{\text {a }}$ |  |  | $\mathrm{E}_{\text {AR }}$ | 5.4 | mJ |
| Maximum Power Dissipation | $\mathrm{T}_{\mathrm{C}}=$ | $5^{\circ} \mathrm{C}$ | $\mathrm{P}_{\mathrm{D}}$ | 54 | W |
|  | $\mathrm{T}_{\text {A }}=$ | $5^{\circ} \mathrm{C}$ |  | 3.1 |  |
| PeaR Diode Recovery dV／dtc，e |  |  | dV／dt | 1.5 | V／ns |

Pb．containing terminations are not RoHS compliant，exemptions may apply
coscom

## IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L

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| ABSOLUTE MAXIMUM RATINGS $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$, unless otherwise noted |  |  |  |  |
| :--- | :---: | :---: | :---: | :---: |
| PARAMETER | SYMBOL | LIMIT | UNIT |  |
| Operating Junction and Storage Temperature Range | $\mathrm{T}_{\mathrm{J},} \mathrm{T}_{\text {stg }}$ | -55 to +150 |  |  |
| Soldering Recommendations (Peak Temperature) | for 10 s |  | $300^{\mathrm{d}}$ |  |
| Mounting Torque | $6-32$ or M3 screw |  | 10 | N |

## Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. $\mathrm{V}_{\mathrm{DD}}=50 \mathrm{~V}$; starting $\mathrm{T}_{J}=25^{\circ} \mathrm{C}, \mathrm{L}=117 \mathrm{mH}, \mathrm{R}_{\mathrm{G}}=25 \Omega, \mathrm{I}_{\mathrm{AS}}=1.7 \mathrm{~A}$ (see fig. 12).
c. $\mathrm{I}_{\mathrm{SD}} \leq 1.7 \mathrm{~A}, \mathrm{~d} / / \mathrm{dt} \leq 70 \mathrm{~A} / \mu \mathrm{s}, \mathrm{V}_{\mathrm{DD}} \leq \mathrm{V}_{\mathrm{DS}}, \mathrm{T}_{\mathrm{J}} \leq 150^{\circ} \mathrm{C}$.
d. 1.6 mm from case.
e. Uses IRFBF20/SiHFBF20 data and test conditions.

| THERMAL RESISTANCE RATINGS |  |  |  |  |
| :--- | :---: | :---: | :---: | :---: |
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient (PCB <br> Mounted, steady-state) |  |  |  |  |
| Maximum Junction-to-Case | $\mathrm{R}_{\text {thJA }}$ | - | 40 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

Note
a. When mounted on 1 " square PCB ( FR-4 or G-10 material).

SPECIFICATIONS $\mathrm{T}_{J}=25^{\circ} \mathrm{C}$, unless otherwise noted

| PARAMETER | SYMBOL | TEST CONDITIONS |  | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Static |  |  |  |  |  |  |  |
| Drain-Source Breakdown Voltage | $\mathrm{V}_{\mathrm{DS}}$ | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=250 \mu \mathrm{~A}$ |  | 900 | - | - | V |
| $V_{\text {DS }}$ Temperature Coefficient | $\Delta \mathrm{V}_{\mathrm{DS}} / \mathrm{T}_{\mathrm{J}}$ | Reference to $25^{\circ} \mathrm{C}, \mathrm{I}_{\mathrm{D}}=1 \mathrm{~mA}$ |  | - | 1.1 | - | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| Gate-Source Threshold Voltage | $\mathrm{V}_{\mathrm{GS}(\text { (th) }}$ | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\mathrm{GS}}, \mathrm{I}_{\mathrm{D}}=250 \mu \mathrm{~A}$ |  | 2.0 | - | 4.0 | V |
| Gate-Source Leakage | $\mathrm{I}_{\text {GSS }}$ | $\mathrm{V}_{\mathrm{GS}}= \pm 20 \mathrm{~V}$ |  | - | - | $\pm 100$ | nA |
| Zero Gate Voltage Drain Current | Idss | $\mathrm{V}_{\mathrm{DS}}=900 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ |  | - | - | 100 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{DS}}=720 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$ |  | - | - | 500 |  |
| Drain-Source On-State Resistance | $\mathrm{R}_{\mathrm{DS} \text { (on) }}$ | $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$ | $\mathrm{I}_{\mathrm{D}}=1.0 \mathrm{~A}^{\mathrm{b}}$ | - | - | 8.0 | $\Omega$ |
| Forward Transconductance | $\mathrm{g}_{\mathrm{fs}}$ | $\mathrm{V}_{\mathrm{DS}}=50 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=1.0 \mathrm{~A}^{\mathrm{b}}$ |  | 0.6 | - | - | S |
| Dynamic |  |  |  |  |  |  |  |
| Input Capacitance | $\mathrm{C}_{\text {iss }}$ | $\begin{gathered} V_{G S}=0 \mathrm{~V}, \\ V_{D S}=25 \mathrm{~V}, \\ f=1.0 \mathrm{MHz} \text {, see fig. } 5 \end{gathered}$ |  | - | 490 | - | pF |
| Output Capacitance | $\mathrm{Cosss}^{\text {a }}$ |  |  | - | 55 | - |  |
| Reverse Transfer Capacitance | $\mathrm{C}_{\text {rss }}$ |  |  | - | 18 | - |  |
| Total Gate Charge | $\mathrm{Q}_{\mathrm{g}}$ | $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$ | $\begin{gathered} I_{D}=1.7 \mathrm{~A}, V_{D S}=360 \mathrm{~V}, \\ \text { see fig. } 6 \text { and } 13^{b} \end{gathered}$ | - | - | 38 | nC |
| Gate-Source Charge | $\mathrm{Q}_{\mathrm{gs}}$ |  |  | - | - | 4.7 |  |
| Gate-Drain Charge | $\mathrm{Q}_{\mathrm{gd}}$ |  |  | - | - | 21 |  |
| Turn-On Delay Time | $\mathrm{t}_{\mathrm{d} \text { (on) }}$ | $\begin{gathered} \mathrm{V}_{\mathrm{DD}}=450 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=1.7 \mathrm{~A}, \\ \mathrm{R}_{\mathrm{G}}=18 \Omega, \mathrm{~V}_{\mathrm{GS}}=10 \mathrm{~V} \text {, see fig. } 10^{\mathrm{b}} \end{gathered}$ |  | - | 8.0 | - | ns |
| Rise Time | $\mathrm{tr}_{\mathrm{r}}$ |  |  | - | 21 | - |  |
| Turn-Off Delay Time | $\mathrm{t}_{\mathrm{d} \text { (off) }}$ |  |  | - | 56 | - |  |
| Fall Time | $\mathrm{t}_{\mathrm{f}}$ |  |  | - | 32 | - |  |

IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L
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| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Drain-Source Body Diode Characteristics |  |  |  |  |  |  |
| Continuous Source-Drain Diode Current | Is | MOSFET symbol showing the integral reverse $\mathrm{p}-\mathrm{n}$ junction diode | - | - | 1.7 | A |
| Pulsed Diode Forward Current ${ }^{\text {a }}$ | $I_{\text {SM }}$ |  | - | - | 6.8 |  |
| Body Diode Voltage | $\mathrm{V}_{\mathrm{SD}}$ | $\mathrm{T}_{J}=25^{\circ} \mathrm{C}, \mathrm{I}_{S}=1.7 \mathrm{~A}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}^{\mathrm{b}}$ | - | - | 1.5 | V |
| Body Diode Reverse Recovery Time | $\mathrm{t}_{\mathrm{rr}}$ | $\mathrm{T}_{J}=25^{\circ} \mathrm{C}, \mathrm{I}_{\mathrm{F}}=1.7 \mathrm{~A}, \mathrm{dl} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s}^{\mathrm{b}}$ | - | 350 | 530 | ns |
| Body Diode Reverse Recovery Charge | $\mathrm{Q}_{\mathrm{rr}}$ |  | - | 0.85 | 1.3 | $\mu \mathrm{C}$ |
| Forward Turn-On Time | $\mathrm{t}_{\text {on }}$ | Intrinsic turn-on time is negligible (turn-on is dominated by $L_{S}$ and $L_{D}$ ) |  |  |  |  |

Notes
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu \mathrm{~s}$; duty cycle $\leq 2 \%$.
c. Uses IRFBF20/SiHFBF20 data and test conditions.

TYPICAL CHARACTERISTICS $25^{\circ} \mathrm{C}$, unless otherwise noted



Fig. 1 - Typical Output Characteristics

## IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L



Fig. 3 - Typical Transfer Characteristics


Fig. 4 - Normalized On-Resistance vs. Temperature


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage


Fig. 7 - Typical Source-Drain Diode Forward Voltage


Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature


Fig. 10a - Switching Time Test Circuit


Fig. 10b - Switching Time Waveforms

## IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L

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Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case


Fig. 12a - Unclamped Inductive Test Circuit


Fig. 12b - Unclamped Inductive Waveforms


Fig. 12c - Maximum Avalanche Energy vs. Drain Current


Fig. 13a - Basic Gate Charge Waveform


Fig. 13b - Gate Charge Test Circuit


Fig. 14 - For N-Channel

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